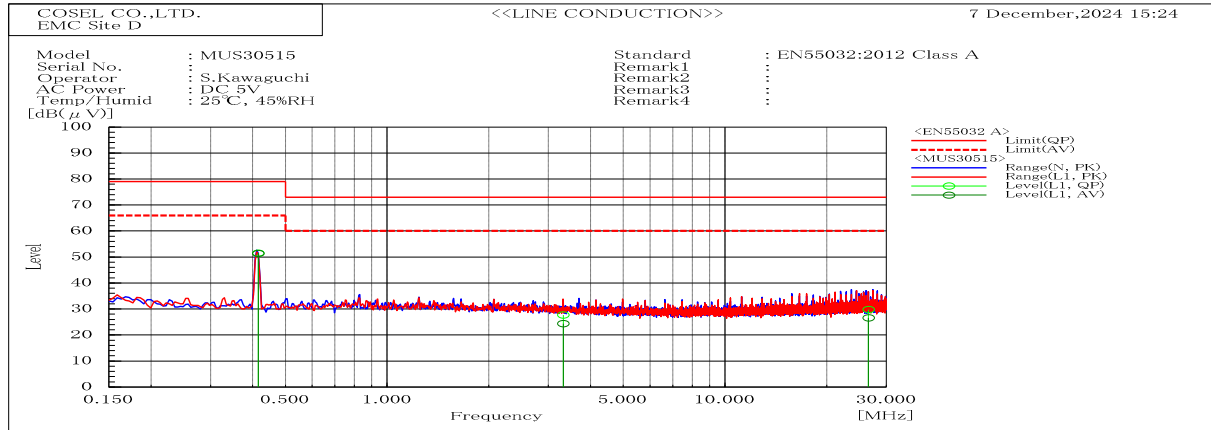
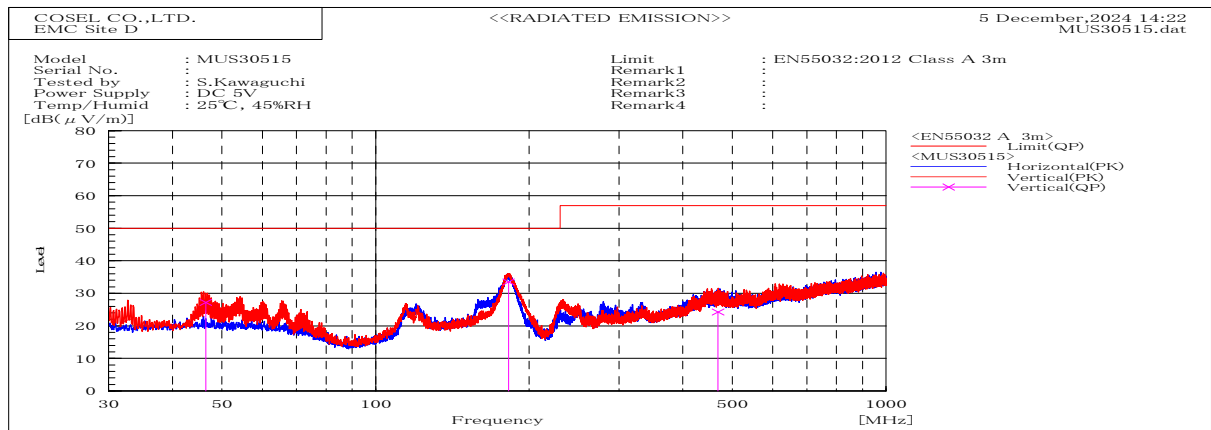


## DATA SHEET

Model		MUS30515	Date	07-Dec-24
Test		EMI Line conduction & Radiated emission	Temp.	25 degreeC
			Humid.	45 %RH
			Tested by	S.Kawaguchi



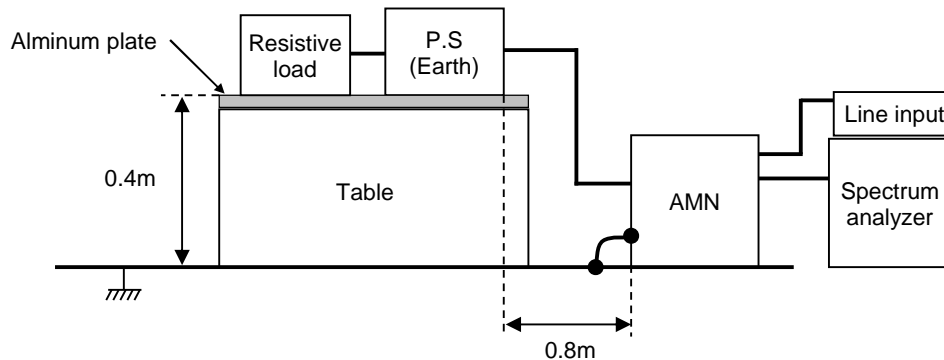
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.415	L1	51.5	51.4	79	66	27.5	14.6	Pass	
3.322	L1	27.7	24.4	73	60	45.3	35.6	Pass	
26.575	L1	29.8	26.6	73	60	43.2	33.4	Pass	



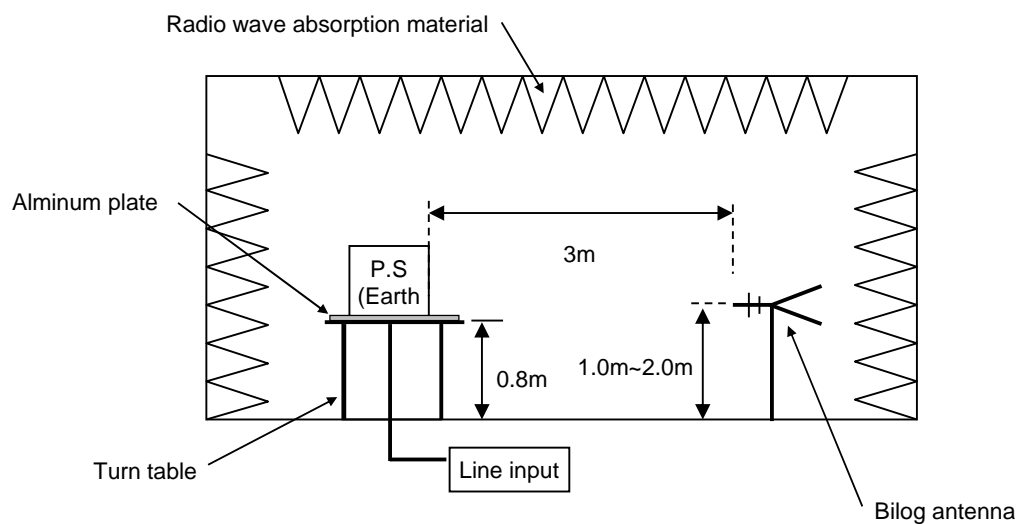
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV						
46.476	V	Stable	27.2	50	22.8	Pass	100.2	0		
182.259	V	Stable	33.5	50	16.5	Pass	100.4	319.4		
468.841	V	Stable	24.3	57	32.7	Pass	198.8	197		

DATA SHEET		Date	07-Dec-24
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

### 1. Line conduction



### 2. Radiated emission



## Conditions

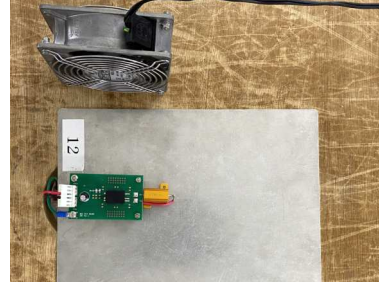
Test : EMI  
Model Name: MUS3□□

## ○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



## ○Testing circuitry

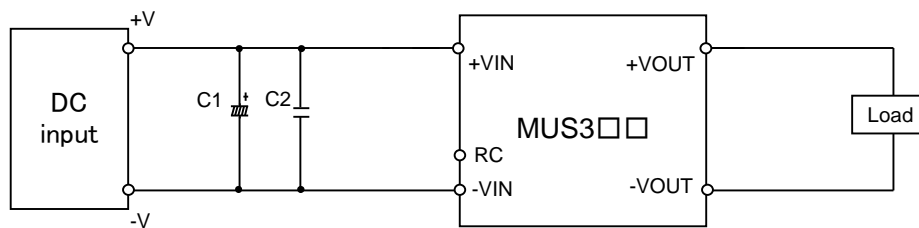


Fig.1 MUS305□, MUS312□, MUS324□ Testing circuitry

C1 :	MUS305□	16V 220 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUS312□	50V 100 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUS324□	-	
C2 :	MUS305□	16V 22 $\mu$ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS312□	25V 22 $\mu$ F	Ceramic capacitor (C3216JB1E226MT TDK)
	MUS324□	50V 10 $\mu$ F	Ceramic capacitor (C3216X7R1H106KT TDK)

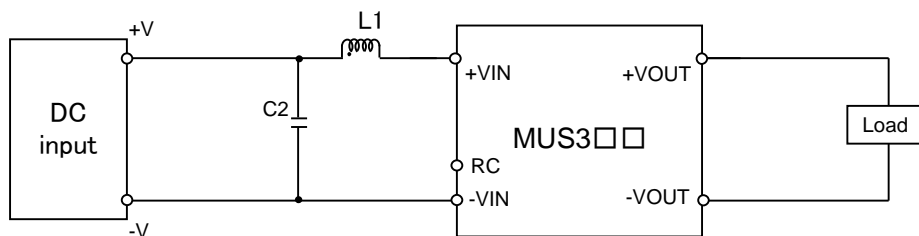


Fig.2 MUS348□ Testing circuitry

C2 :	MUS348□	100V 2.2 $\mu$ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS348□	520mA 15 $\mu$ H	Inductor(LQH32PN150MN0L MURATA MANUFACTURING)